

| Title of Change: | Mold Compound Change attributed to an End of Life of Samsung SDI EMC for products in TO247 package. | |
|--|--|--|
| Proposed Changed Material First Ship Date: | 24 September 2020 | |
| Current Material Last Order Date: | 30 May 2020 Orders received after the Current Material Last Order Date expiration are to be considered as orders new changed material as described in this PCN. Orders for current (unchanged) material after this of will be per mutual agreement and current material inventory availability. | |
| Current Material Last Delivery Date: | 23 September 2020 The Current Material Last Delivery Date may be subject to change based on build and depletion of the current (unchanged) material inventory. | |
| Product Category: | Active components – Discrete components | |
| Contact information: | Contact your local ON Semiconductor Sales Office or < <u>Peter.lee@onsemi.com</u> > | |
| Samples: | Contact your local ON Semiconductor Sales Office to place sample order or < <u>PCN.samples@onsemi.com</u> Sample requests are to be submitted no later than 45 days after publication of this change notification. | |
| Sample Availability Date: | 31 October 2019 Samples delivery timing will be subject to request date, sample quantity and special custome packing/label requirements. | |
| PPAP Availability Date: | 1 October 2019 | |
| Additional Reliability Data: | Contact your local ON Semiconductor Sales Office or < <u>Frank.Tuan@onsemi.com</u> >. | |
| Type of Notification: | This is a Final Product/Process Change Notification (FPCN) sent to customers. FPCNs are issued 12 months prior to implementation of the change or earlier upon customer approval. ON Semiconductor will consider this proposed change and it's conditions acceptable, unless an inquiry made in writing within 45 days of delivery of this notice. To do so, contact PCN.Support@onsemi.com | |
| Change Category | Type of Change | |
| Process – Assembly | Change of mold compound | |
| Description and Purpose: ON Semiconductor wishes to inform o | bur customers of a change in mold compounds used for the devices listed in this PCN. This is the final product | |

ON Semiconductor wishes to inform our customers of a change in mold compounds used for the devices listed in this PCN. This is the final product change notification (FPCN) of IPCN22647. This change is a result of an End of Life notification received from Samsung for several of their SDI Mold Compounds. Due to the discontinuance of the SDI mold compounds, ON Semiconductor will only have limited supplies of the existing material and in some cases this may not allow for the normal change notification period.

All other aspects of the impacted products (form, fit, function) will remain unchanged.

| | Before Change Description | After Change Description |
|---------------|---------------------------------|--------------------------|
| Mold compound | SG8200DL, Supplier: Samsung SDI | KTMC1050GFA |

There is no product marking change as a result of this change

| Reason / Motivation for Change: | The motivation of change is to have better capacity support mass production Late release from customer has potential supply issue. |
|------------------------------------|---|
| Change: | - Late release nom customer has potential supply issue. |



Issue Date: 24 September 2019

| Anticipated impact on fit, form, function, reliability, product safety or manufacturability | The device has been qualified and validated based on the same Product Specification. The device has successfully passed the qualification tests. Potential impacts can be identified, but due to testing performed by ON Semiconductor in relation to the PCN, associated risks are verified and excluded. No anticipated impacts. | | |
|---|--|--|--|
| Sites Affected: | ON Semiconductor Sites: ON Suzhou, China | External Foundry/Subcon Sites: None | |
| Marking of Parts/ Traceability of Change: | Customer may receive the parts from ON Semiconductor from month of 30 August 2020 onwards one FPCN expire. Parts from ON Semiconductor can be identified through product marking which follow OI Semiconductor marking format. | | |

Reliability Data Summary:

:SVHL080N120SC1 Device RMS :<u>U56692</u> PACKAGE :TO247

| Test | Specification | Condition | Interval | Results |
|----------------|--------------------------------|--|----------|---------|
| HTRB | JESD22-A108 | Ta = 175°C for device, bias = 100% of max rated | 1008 hrs | 0/231 |
| HTGB | JESD22-A108 | Ta = 175°C for 1008 hours, 100% rated Vgs | 1008 hrs | 0/231 |
| HTSL | JESD22-A103 | Ta = 175°C for 1008 hours | 1008 hrs | 0/231 |
| TC | JESD22-A104 | Temp = -55°C to +150°C; for 1000 cycles | 1000 cyc | 0/231 |
| IOL | MIL STD750, M 1037 AEC Q101 | Ta=+25°C, delta Tj=100°C max, Ton=Toff is 3.5min | 8572Cyc | 0/231 |
| HAST | JESD22 A110 | Temp= +110°C, RH=85% , 264hr, bias = 80% of rated BV or 100V max | 264hrs | 0/231 |
| RSH | JESD22-B106 | 265 °C Immersion and 10s | 10s | 0/30 |
| SD | J STD 002 | Ta=245°C 5 sec dwell | 5s | 0/45 |
| PD | | Per Case Outline | | 0/30 |
| Tri-temp | | Tri-Temp Characterization, Per 48A | | 0/90 |
| TR | | Thermal Resistance | | 0/30 |
| CDPA TCDT | AEC Q101, rev D, test 7A (alt) | Custom Destructive Physical Analysis - TC Delamination Test, Post 1000 cyc TC | | 0/66 |
| CDPA SAT | AEC-006 | Post HTRB,HTGB | | 0/66 |
| DPA | AEC-Q101-004 Section 4 | Destructive Physical Analysis Post TC, HAST, HTRB, HTGB | | 0/6 |
| CDPA WP BS | MIL 883E, AEC -006 | Custom Destructive Physical Analysis - Wire Pull, Ball Shear Post TC, HTRB, HTGB | | 0/18 |
| CDPA X Section | AEC -006 | Post TC, HTRB, HTGB | | 0/9 |
| Shift | | Shift Analysis for HTRB/HTGB/HTSL/TC/IOL/HAST | | Pass |



| : <u>FFSH40120AD</u> : <u>U56690</u> GE : <u>TO247</u> | <u>9N-F085</u> | | | |
|---|--------------------------------|--|----------|---------|
| Test | Specification | Condition | Interval | Results |
| HTRB | JESD22-A108 | Ta = 175°C for device, bias = 100% of max rated | 1008 hrs | 0/231 |
| HTSL | JESD22-A103 | Ta = 175°C for 1008 hours | 1008 hrs | 0/231 |
| тс | JESD22-A104 | Temp = -55°C to +150°C; for 1000 cycles | 1000 сус | 0/231 |
| HAST | JESD22 A110 | Temp= +110°C, RH=85% , 264hr, bias = 80% of rated BV or 100V max | 264hrs | 0/231 |
| RSH | JESD22-B106 | 265 °C Immersion and 10s | 10s | 0/30 |
| SD | J STD 002 | Ta=245°C 5 sec dwell | 5s | 0/45 |
| PD | | Per Case Outline | | 0/30 |
| Tri-temp | | Tri-Temp Characterization, Per 48A | | 0/90 |
| TR | | Thermal Resistance | | 0/30 |
| CDPA TCDT | AEC Q101, rev D, test 7A (alt) | Custom Destructive Physical Analysis - TC Delamination Test, Post 1000 cyc TC | | 0/66 |
| CDPA SAT | AEC-006 | Post HTRB | | 0/66 |
| DPA | AEC-Q101-004 Section 4 | Destructive Physical Analysis Post TC, HAST, HTRB | | 0/6 |
| CDPA WP BS | MIL 883E, AEC -006 | Custom Destructive Physical Analysis - Wire Pull, Ball Shear Post TC, HTRB | | 0/18 |
| CDPA X Section | AEC -006 | Post TC, HTRB | | 0/9 |
| Shift | | Shift Analysis for HTRB/HTSL/TC/HAST | | Pass |

Note: AEC-1pager is attached.

To view attachments:

- 1. Download pdf copy of the PCN to your computer
- 2. Open the downloaded pdf copy of the PCN
- 3. Click on the paper clip icon available on the menu provided in the left/bottom portion of the screen to reveal the Attachment field
- 4. Then click on the attached file/s

Electrical Characteristic Summary:

Electrical characteristics are not impacted.



List of Affected Parts:

Note: Only the standard (off the shelf) part numbers are listed in the parts list. Any custom parts affected by this PCN are shown in the customer specific PCN addendum in the PCN email notification, or on the **PCN Customized Portal**.

| Current Part Number | Qualification Vehicle |
|---------------------|-----------------------|
| FFSH10120A-F085 | FFSH40120ADN-F085 |
| FFSH20120ADN-F085 | FFSH40120ADN-F085 |
| FFSH20120A-F085 | FFSH40120ADN-F085 |
| FFSH2065BDN-F085 | FFSH40120ADN-F085 |
| FFSH3065B-F085 | FFSH40120ADN-F085 |
| FFSH40120ADN-F085 | FFSH40120ADN-F085 |
| FFSH1065B-F085 | FFSH40120ADN-F085 |
| NVHL080N120SC1 | SVHL080N120SC1 |
| FFSH2065B-F085 | FFSH40120ADN-F085 |
| FFSH4065BDN-F085 | FFSH40120ADN-F085 |
| FFSH5065B-F085 | FFSH40120ADN-F085 |
| FFSH1265BDN-F085 | FFSH40120ADN-F085 |